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				Application Number	10/665,970
				Filing Date	September 18, 2003
				First Named Inventor:	Soma et al.
				Art Unit	2863
				Examiner Name	Bryan Bui
Sheet	2	of	2	Attorney Docket Number	4735.P005
<b>NON PATENT LITERATURE DOCUMENTS</b>					
Examiner Initials*	Cite No <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published			T <sup>2</sup>
B	2	BOUWMAN, F. et al., "Application of Joint Time-Frequency Analysis in Mixed Signal Testing," Proc. IEEE International Test Conference, pp. 747-756, Washington, DC, 1994.			
	3	YAMAGUCHI, T.J. et al., "Dynamic Testing of ADCs Using Wavelet Transforms," Proc. IEEE International Test Conference, pp. 379-388, Washington, DC, 1997.			
	4	SUNTER, S. et al., "BIST for Phase-Locked Loops in Digital Applications," Proc. IEEE International Test Conference, pp. 532-540, Sept. 28-30, 1999, Atlantic City, NJ.			
	5	MASON, R. et al., "Mixed Signal DFT at GHz Frequencies," J. of Electronic Testing: Theory and Applications 15, pp. 31-39, 1999.			
	6	ROH, J. et al., "Subband Filtering Scheme for Analog and Mixed-Signal Circuit Testing," Proc. IEEE International Test Conference, pp. 221-229, Atlantic City, NJ, 1999.			
	7	YAMAGUCHI, T.J. et al., "Jitter Measurements of a PowerPC Microprocessor Using An Analytic Signal Method," Proc. IEEE International Test Conference, pp. 955-964, Atlantic City, NJ, 2000.			
	8	CHAN, A.H. et al., "A Synthesizable, Fast and High-Resolution Timing Measurement Device Using a Component-Invariant Vernier Delay Line," Proc. IEEE International Test Conference, pp. 858-867, Baltimore, MD, 2001.			
	9	BHUNIA, S. et al., "Dynamic Supply Current Testing of Analog Circuits Using Wavelet Transform," Proc. IEEE VLSI Test Symposium, pp. 302-307, Monterey, CA, 2002.			

Examiner Signature		Date Considered	5/20/06
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\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. <sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>Applicant is to place a check mark here if English translation is attached.

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